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(71) Applicant (for all designated States except US): **OM-NIPROBE, Inc.** [US/US]; 7738 Forest Lane, #426, Dallas, Texas 75230 (US).

(72) Inventor; and

(75) Inventor/Applicant (for US only): **MOORE, Thomas** [US/US]; 7738 Forest Lane, #426, Dallas, Texas 75230 (US).

(74) Agent: **THOMAS, John A.**; 2200 One Galleria Tower, 13355 Noel Road, L.B. 48, Dallas, Texas 75240-1518 (US).

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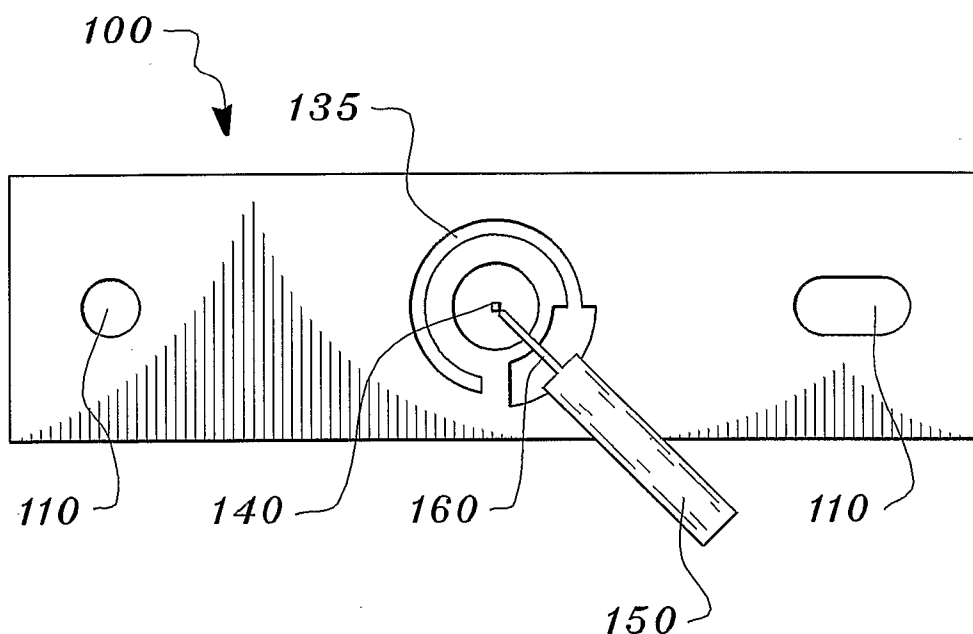
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(54) Title: METHOD AND APPARATUS FOR RAPID SAMPLE PREPARATION IN A FOCUSED ION BEAM MICROSCOPE



(57) Abstract: A coupon (100) for preparing a TEM sample holder (170) comprises a sheet of material (120) that includes a TEM sample holder form (170). There is at least one section of the sheet (120) connecting the TEM sample holder form (170) to other portions of the sheet (120). A TEM sample holder (170) is formed by cutting the TEM sample holder form (170) from the coupon (100) in a press. The cutting joins the tip point (160) of a nano-manipulator probe tip (150) with the formed TEM sample holder (170). The tip point (160) of the probe (150) has a sample (140) attached for inspection in a TEM.



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